Image Sensors and Companion Chips

Guest Editor:

Dr. Kaiming Nie
School of Microelectronics,
Tianjin University, Tianjin 300072,
China

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Message from the Guest Editor

CMOS image sensors are highly integrated optoelectronic chips which convert optical information into digital information that is easy to process and store. With the development of 3D integration and packaging technology, multiple chips can be integrated into one chip to form more compact imaging systems.

This Special Issue encourages researchers to present their theories, techniques, circuits, and systems of CMOS chips for image sensing and companion chips. The scope of this Special Issue focuses on, but is not limited to:

- CMOS image sensor modeling;
- High-performance active pixels;
- Low-noise readout circuits;
- High-speed imaging techniques;
- Dynamic range extension technology;
- Low-light imaging;
- High-resolution imaging;
- 3D imaging;
- Dynamic vision sensors;
- Spike-based image sensors;
- Sensory and computational integration;
- Image signal processing;
- Single photon counting technique;
- Image sensor interfaces.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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